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 - L1: (1) ("5930634").PN.
 - L2: (1) ("6509586").PN.
 - L3: (1504) 257/401.CCL5.
 - L4: (1504) 257/401.CCL5.3 and (field adj effect ad transistor "FET")
 - L5: (218) 4 and (ring annular)
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Plurals

Default operator.

☒ Highlight all hit terms initially

4 and (ring annular)

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	
62	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6509617 B2	20030121		Semiconductor device and fabrication method thereof	257/409	257/355; 257/401; 257/E29.013.	
63	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6492691 B2	20021210		High integration density MOS technology power device structure	257/401	257/339; 257/341; 257/409.	
64	<input type="checkbox"/>	<input type="checkbox"/>	US 6489658 B2	20021203	6	MOS-transistor for a photo cell	257/401	257/465; 257/466; 257/E27.132.	
65	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6448596 B1	20020910	40	Solid-state imaging device	257/292	257/291; 257/401; 257/E27.132.	
66	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6445036 B1	20020903	16	Semiconductor device having trench-structured rectangular unit cells	257/330	257/331; 257/335; 257/401.	
67	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6420766 B1	20020716	43	Transistor having raised source and drain	257/401	257/327; 257/622; 257/E21.027.	
68	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6420757 B1	20020716	18	Semiconductor diodes having low forward conduction voltage drop, low reverse current leakage, and high avalanche energy capability	257/341	257/401; 257/601; 257/E21.357.	
69	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6407434 B1	20020618	136	Hexagonal architecture	257/401	257/207; 257/211; 257/258.	
70	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6399991 B1	20020604	11	Semiconductor integrated circuit	257/355	257/350; 257/360; 257/401.	
71	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6359291 B1	20020319	24	Corrosion resistant imager	257/72	257/401; 257/763; 257/765.	
72	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6326656 B1	20011204	5	Lateral high-voltage transistor	257/288	257/339; 257/345; 257/355.	